









SN74LVC1T45 SCES515N - DECEMBER 2003 - REVISED JUNE 2024

# SN74LVC1T45 Single-Bit Dual-Supply Bus Transceiver With Configurable Voltage **Translation and 3-State Outputs**

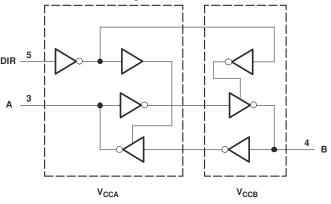
#### 1 Features

- ESD protection exceeds JESD 22:
  - 2000V Human-Body Model (A114-A)
  - 200V Machine Model (A115-A)
  - 1000V Charged-Device Model (C101)
- Available in the Texas Instruments NanoFree™ package
- Fully configurable dual-rail design allows each port to operate over the full 1.65V to 5.5V power-supply
- V<sub>CC</sub> isolation feature if either V<sub>CC</sub> input is at GND, both ports are in the high-impedance state
- DIR input circuit referenced to V<sub>CCA</sub>
- Low power consumption, 4µA maximum I<sub>CC</sub>
- ±24mA output drive at 3.3V
- I<sub>off</sub> supports partial-power-down mode operation
- Maximum data rates
  - 420Mbps (3.3V to 5V translation)
  - 210Mbps (translate to 3.3V)
  - 140Mbps (translate to 2.5V)
  - 75Mbps (translate to 1.8V)
- Latch-up performance exceeds 100mA per JESD 78, Class II

### 2 Applications

- Personal electronic
- Industrial
- **Enterprise**
- **Telecom**

### **Functional Block Diagram**



# 3 Description

This single-bit noninverting bus transceiver uses two separate configurable power-supply rails. The A port is designed to track V<sub>CCA</sub>. V<sub>CCA</sub> accepts any supply voltage from 1.65V to 5.5V. The B port is designed to track V<sub>CCB</sub>. V<sub>CCB</sub> accepts any supply voltage from 1.65V to 5.5V. This allows for universal low-voltage bidirectional translation between any of the 1.8V, 2.5V, 3.3V, and 5V voltage nodes.

The SN74LVC1T45 is designed for asynchronous communication between two data buses. The logic levels of the direction-control (DIR) input activate either the B-port outputs or the A-port outputs. The device transmits data from the A bus to the B bus when the B-port outputs are activated and from the B bus to the A bus when the A-port outputs are activated. The input circuitry is always active on both A and B ports and must have a logic HIGH or LOW level applied to prevent excess I<sub>CC</sub> and I<sub>CC7</sub>.

The SN74LVC1T45 is designed so that the DIR input is powered by V<sub>CCA</sub>. This device is fully specified for partial-power-down applications using Ioff. The Ioff circuitry disables the outputs, preventing damaging current backflow through the device when it is powered down. The V<sub>CC</sub> isolation feature is designed so that if either V<sub>CC</sub> input is at GND, then both ports are in the high-impedance state.

NanoFree™ package technology is a major breakthrough in IC packaging concepts, using the die as the package.

**Package Information** 

PART NUMBER	PACKAGE <sup>(1)</sup>	PACKAGE SIZE(2)	
	DRL (SOT, 6)	1.6mm × 1.6mm	
	DBV (SOT-23, 6)	2.9mm × 2.8mm	
SN74LVC1T45	DCK (SC70, 6)	2mm × 2.1mm	
	DPK (USON, 6)	1.6mm × 1.6mm	
	YZP (DSBGA, 6)	1mm × 0.5mm	

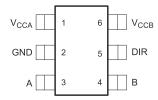
- For more information, see Section 11.
- The package size (length × width) is a nominal value and includes pins, where applicable.



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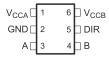
# **4 Pin Configuration and Functions**



GND 2 5 DIR
A 3 4 B

Figure 4-2. DCK Package, 6-Pin SC70 (Top View)

Figure 4-1. DBV Package, 6-Pin SOT-23 (Top View)



GND 2 5 DIR
A 3 4 B

Figure 4-3. DRL Package, 6-Pin SOT (Top View)

Figure 4-4. DPK Package, 6-Pin USON (Top View)

6 VCCB

#### Table 4-1. Pin Functions

	PIN		
NAME	DBV, DCK, DRL, DPK	TYPE <sup>(1)</sup>	DESCRIPTION
V <sub>CCA</sub>	1	Р	SYSTEM-1 supply voltage (1.65V to 5.5V)
GND	2	G	Device GND
Α	3	I/O	Output level depends on V <sub>CC1</sub> voltage.
В	4	I/O	Input threshold value depends on V <sub>CC2</sub> voltage.
DIR	5	I	GND (low level) determines B-port to A-port direction.
V <sub>CCB</sub>	6	Р	SYSTEM-2 supply voltage (1.65V to 5.5V)

(1) P = power, G = ground, I/O = input and output, I = input



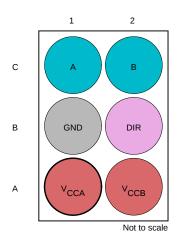


Figure 4-5. YZP Package, 6-Pin DSBGA (Bottom View)

Leg	end
Power	Input
Input or Output	Ground

**Table 4-2. Pin Functions** 

	PIN	TYPE <sup>(1)</sup>	DESCRIPTION
NO.	NAME	ITPE\'	DESCRIPTION
A1	V <sub>CCA</sub>	Р	SYSTEM-1 supply voltage (1.65V to 5.5V)
A2	V <sub>CCB</sub>	Р	SYSTEM-2 supply voltage (1.65V to 5.5V)
B1	GND	G	Device GND
B2	DIR	I	GND (low level) determines B-port to A-port direction.
C1	Α	I/O	Output level depends on V <sub>CC1</sub> voltage.
C2	В	I/O	Input threshold value depends on V <sub>CC2</sub> voltage.

(1) P = power, G = ground, I/O = input and output, I = input

# **5 Specifications**

### 5.1 Absolute Maximum Ratings

over operating free-air temperature range (unless otherwise noted) (1)

		·	MIN	MAX	UNIT
V <sub>CCA</sub> V <sub>CCB</sub>	Supply voltage		-0.5	6.5	V
VI	Input voltage <sup>(2)</sup>		-0.5	6.5	V
Vo	Voltage range applied to any output in the high-impeda	-0.5	6.5	V	
Vo	Voltage range applied to any output in the high or low	A port	-0.5	V <sub>CCA</sub> + 0.5	V
	state <sup>(2) (3)</sup>	B port	-0.5	V <sub>CCB</sub> + 0.5	V
I <sub>IK</sub>	Input clamp current	V <sub>1</sub> < 0		-50	mA
I <sub>OK</sub>	Output clamp current	V <sub>O</sub> < 0		-50	mA
Io	Continuous output current			±50	mA
	Continuous current through V <sub>CC</sub> or GND		±100	mA	
TJ	Junction temperature		150	°C	
T <sub>stg</sub>	Storage temperature		-65	150	°C

<sup>(1)</sup> Stresses beyond those listed under Absolute Maximum Ratings may cause permanent damage to the device. These are stress ratings only, which do not imply functional operation of the device at these or any other conditions beyond those indicated under Recommended Operating Conditions. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- (2) The input and output negative-voltage ratings may be exceeded if the input and output clamp-current ratings are observed.
- (3) The value of V<sub>CC</sub> is provided in the Recommended Operating Conditions table.

# 5.2 ESD Ratings

			VALUE	UNIT
		Human-body model (HBM), per ANSI/ESDA/JEDEC JS-001 <sup>(1)</sup>	±2000	
V <sub>(ESD)</sub>	Electrostatic discharge	Charged-device model (CDM), per JEDEC specification JESD22-C101 <sup>(2)</sup>	±1000	V
		Machine Model	±200	

- (1) JEDEC document JEP155 states that 500V HBM allows safe manufacturing with a standard ESD control process.
- (2) JEDEC document JEP157 states that 250V CDM allows safe manufacturing with a standard ESD control process.

### **5.3 Recommended Operating Conditions**

### See (1) (2) (3)

			V <sub>CCI</sub>	V <sub>cco</sub>	MIN	MAX	UNIT				
V <sub>CCA</sub>	Supply voltage				1.65	5.5	V				
V <sub>CCB</sub>	Supply voltage				1.65	5.5	V				
			1.65 o 1.95V		V <sub>CCI</sub> × 0.65						
	High-level	Data inputa(4)	2.3 to 2.7V		1.7		V				
V <sub>IH</sub>	input voltage		3 to 3.6V		2		V				
			4.5 to 5.5V		V <sub>CCI</sub> × 0.7						
		ow-level	1.65 o 1.95V			V <sub>CCI</sub> × 0.35					
,,	Low-level		2.3 to 2.7V			0.7	V				
V <sub>IL</sub>	input voltage	Data inputs <sup>(4)</sup>	3 to 3.6V			0.8	V				
			4.5 to 5.5V			V <sub>CCI</sub> × 0.3					
			1.65 to 1.95V		V <sub>CCA</sub> × 0.65						
,,	High-level	ligh-level DIR	2.3 to 2.7V		1.7						
V <sub>IH</sub>	input voltage					3 to 3.6V		2		V	
					V <sub>CCA</sub> × 0.7						

Product Folder Links: SN74LVC1T45

# 5.3 Recommended Operating Conditions (continued)

See (1) (2) (3)

			V <sub>CCI</sub>	V <sub>cco</sub>	MIN	MAX	UNIT	
			1.65 to 1.95V		V	V <sub>CCA</sub> × 0.35		
V	Low-level	DIR	2.3 to 2.7V			0.7	V	
$V_{IL}$	input voltage	(referenced to V <sub>CCA</sub> ) <sup>(5)</sup>	3 to 3.6V			0.8	V	
			4.5 to 5.5V		•	V <sub>CCA</sub> × 0.3		
VI	Input voltage				0	5.5	V	
Vo	Output voltage				0	V <sub>cco</sub>	V	
I <sub>OH</sub>				1.65 to 1.95V		-4		
	High-level output current			2.3 to 2.7V		-8	m A	
				3 to 3.6V		-24	mA	
				4.5 to 5.5V		-32		
		Low-level output current		1.65 to 1.95V		4		
	Low lovel output or			2.3 to 2.7V		8	m A	
l <sub>OL</sub>	Low-level output ct			3 to 3.6V		24	mA	
				4.5 to 5.5V		32		
			1.65 to 1.95V			20		
		Data inputa	2.3 to 2.7V			20		
Δt/Δν	Input transition rise or fall rate		3 to 3.6V			10	ns/V	
	1.00 or idir idio		4.5 to 5.5V			5		
		Control inputs	1.65 to 5.5V			5		
T <sub>A</sub>	Operating free-air t	emperature			-40	85	°C	

- (2)
- $V_{CCI}$  is the  $V_{CC}$  associated with the input port.  $V_{CCO}$  is the  $V_{CC}$  associated with the output port. All unused data inputs of the device must be held at  $V_{CCI}$  or GND to ensure proper device operation. See the TI application report, Implications of Slow or Floating CMOS Inputs, SCBA004.
- (4) For  $V_{CCI}$  values not specified in the data sheet,  $V_{IH}$  min =  $V_{CCI} \times 0.7V$ ,  $V_{IL}$  max =  $V_{CCI} \times 0.3V$ . (5) For  $V_{CCI}$  values not specified in the data sheet,  $V_{IH}$  min =  $V_{CCA} \times 0.7V$ ,  $V_{IL}$  max =  $V_{CCA} \times 0.3V$ .

### **5.4 Thermal Information**

THERMAL METRIC <sup>(1)</sup>							
		DBV (SOT-23)	DCK (SC70)	DPK (USON)	DRL (SOT)	YZP (DSBGA)	UNIT
				6 PINS			
$R_{\theta JA}$	Junction-to-ambient thermal resistance	215.1	210.9	278.3	223.7	131.0	°C/W
R <sub>θJC(top)</sub>	Junction-to-case (top) thermal resistance	136.5	139.2	133.4	88.7	1.3	°C/W
$R_{\theta JB}$	Junction-to-board thermal resistance	96.6	72	174.1	58.4	22.6	°C/W
ΨЈТ	Junction-to-top characterization parameter	71.5	54.9	23.4	5.9	5.2	°C/W
ΨЈВ	Junction-to-board characterization parameter	96.3	71.7	173.5	58.1	22.6	°C/W

For more information about traditional and new thermal metrics, see the Semiconductor and IC Package Thermal Metrics application report.



### **5.5 Electrical Characteristics**

over recommended operating free-air temperature range,  $T_A = -40$  to +85°C (unless otherwise noted)(1)(2)

PARA	METER	TEST CONDI	TIONS	V <sub>CCA</sub>	Vc	СВ	MIN	TYP	MAX	UNIT
		I <sub>OH</sub> = -100μA		1.65 to 4.5V	1.65 to	4.5V	V <sub>CCO</sub> - 0.1			
		I <sub>OH</sub> = –4mA		1.65V	1.6	5V	1.2			
$V_{OH}$		I <sub>OH</sub> = -8mA	V <sub>I</sub> = V <sub>IH</sub>	2.3V	2.3	V	1.9			V
		I <sub>OH</sub> = -24mA		3V	3\	/	2.4			
		I <sub>OH</sub> = -32mA		4.5V	4.5	ίV	3.8			
	I <sub>OL</sub> = 100μA			1.65 to 4.5V	1.65 to	4.5V			0.1	
		I <sub>OL</sub> = 4mA		1.65V	1.6	5V			0.45	
$V_{OL}$			$V_I = V_{IL}$	2.3V	2.3	V			0.3	V
· OL		I <sub>OL</sub> = 24mA		3V	3\	/			0.55	
		I <sub>OL</sub> = 32mA		4.5V	4.5	ίV			0.55	
						T <sub>A</sub> = 25 °C			±1	
I <sub>I</sub>	DIR	V <sub>I</sub> = V <sub>CCA</sub> or GND		1.65 to 5.5V	1.65 to 5.5V	T <sub>A</sub> = -40 to +85°C			±2	μΑ
						T <sub>A</sub> = 25 °C			±1	
	A port	V or V = 0 to 5.5	<b>.</b>	0V	0 to 5.5V	T <sub>A</sub> = -40 to +85°C			±2	
l <sub>off</sub>		$V_1$ or $V_0 = 0$ to 5.5V				T <sub>A</sub> = 25 °C	±1 ±2			μA
	B port			0 to 5.5V	0V	T <sub>A</sub> = -40 to +85°C				
	A or B					T <sub>A</sub> = 25 °C			±1	
l <sub>OZ</sub>	port	$V_O = V_{CCO}$ or GNE	)	1.65 to 5.5V	1.65 to 5.5V	T <sub>A</sub> = -40 to +85°C			±2	μA
				1.65 to 5.5V	1.65 to 5.5V				3	
$I_{CCA}$		$V_I = V_{CCI}$ or GND,	$I_O = 0$	5.5V	0\	/			2	μΑ
				0V	5.5	ίV			-2	
				1.65 to 5.5V	1.65 to	5.5V			3	
$I_{CCB}$		$V_I = V_{CCI}$ or GND,	$I_O = 0$	5.5V	0\	/			-2	μΑ
				0V	5.5	ίV			2	
I <sub>CCA</sub> + (see Ta	I <sub>CCB</sub> able 7-1)	$V_I = V_{CCI}$ or GND,	I <sub>O</sub> = 0	1.65 to 5.5V	1.65 to	5.5V			4	μΑ
	A port	A port at V <sub>CCA</sub> – 0 DIR at V <sub>CCA</sub> , B po							50	
ΔI <sub>CCA</sub>	DIR	DIR at V <sub>CCA</sub> – 0.6\\ B port = open, A port at V <sub>CCA</sub> or 0		3 to 5.5V	3 to 5.5V				μA	
ΔI <sub>CCB</sub>	B port	B port at V <sub>CCB</sub> – 0 DIR at GND, A port = open	6V,	3 to 5.5V	3 to 5.5V				50	μA
C <sub>i</sub>	DIR	$V_I = V_{CCA}$ or GND		3.3V	3.3V	T <sub>A</sub> = 25 °C		2.5		pF
C <sub>io</sub>	A or B port	$V_{O} = V_{CCA/B}$ or GN	ID	3.3V	3.3V	T <sub>A</sub> = 25 °C		6		pF

 $<sup>\</sup>begin{array}{ll} \hbox{(1)} & V_{CCO} \text{ is the } V_{CC} \text{ associated with the output port.} \\ \hbox{(2)} & V_{CCI} \text{ is the } V_{CC} \text{ associated with the input port.} \end{array}$ 

# 5.6 Switching Characteristics ( $V_{CCA} = 1.8V \pm 0.15V$ )

over recommended operating free-air temperature range,  $V_{CCA}$  = 1.8V  $\pm$  0.15V (see Figure 6-1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V <sub>CCB</sub> = ±0.15	1.8V	V <sub>CCB</sub> = ±0.2		V <sub>CCB</sub> = ±0.3		V <sub>CCB</sub> = ±0.5		UNIT
	(iidi 01)	(001701)	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	
t <sub>PLH</sub>	Α	В	3	17.7	2.2	10.3	1.7	8.3	1.4	7.2	ns
t <sub>PHL</sub>		В	2.8	14.3	2.2	8.5	1.8	7.1	1.7	7	115
t <sub>PLH</sub>	В	А	3	17.7	2.3	16	2.1	15.5	1.9	15.1	ne
t <sub>PHL</sub>		A	2.8	14.3	2.1	12.9	2	12.6	1.8	12.2	ns
t <sub>PHZ</sub>	DIR	А	5.2	19.4	4.8	18.5	4.7	18.4	5.1	17.1	20
t <sub>PLZ</sub>		A	2.3	10.5	2.1	10.5	2.4	10.7	3.1	10.9	ns
t <sub>PHZ</sub>	DIR	В	5.2	21.9	4.9	11.5	4.6	10.3	2.8	8.2	ns
t <sub>PLZ</sub>	DIK	В	4.2	16	3.7	9.2	3.3	8.4	2.4	6.4	115
t <sub>PZH</sub> (1)	DIR	А		33.7		25.2		23.9		21.5	ns
t <sub>PZL</sub> (1)	DIK			36.2		24.4		22.9		20.4	115
t <sub>PZH</sub> (1)	DIR	В		28.2		20.8		19		18.1	20
t <sub>PZL</sub> (1)	אוט	D		33.7		27		25.5		24.1	ns

<sup>(1)</sup> The enable time is a calculated value, derived using the formula shown in the *Enable Times* section.

# 5.7 Switching Characteristics ( $V_{CCA} = 2.5V \pm 0.2V$ )

over recommended operating free-air temperature range,  $V_{CCA} = 2.5V \pm 0.2V$  (see Figure 6-1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V <sub>CCB</sub> = ±0.15		V <sub>CCB</sub> = ±0.2		V <sub>CCB</sub> = ±0.3		V <sub>CCB</sub> = ±0.5		UNIT
	(INPUT)		MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	
t <sub>PLH</sub>	А	В	2.3	16	1.5	8.5	1.3	6.4	1.1	5.1	ns
t <sub>PHL</sub>	A	В	2.1	12.9	1.4	7.5	1.3	5.4	0.9	4.6	115
t <sub>PLH</sub>	В	А	2.2	10.3	1.5	8.5	1.4	8	1	7.5	20
t <sub>PHL</sub>	ь		2.2	8.5	1.4	7.5	1.3	7	0.9	6.2	6.2 ns
t <sub>PHZ</sub>	DIR	А	3	8.1	3.1	8.1	2.8	8.1	3.2	8.1	ns
t <sub>PLZ</sub>	DIK	_ ^	1.3	5.9	1.3	5.9	1.3	5.9	1	5.8	
t <sub>PHZ</sub>	DIR	В	5.2	23.7	4.1	11.4	3.9	10.2	2.4	7.1	ns
t <sub>PLZ</sub>	DIK	В	3.9	18.9	3.2	9.6	2.8	8.4	1.8	5.3	115
t <sub>PZH</sub> (1)	DID	А		29.2		18.1		16.4		12.8	20
t <sub>PZL</sub> <sup>(1)</sup>	DIR			32.2		18.9		17.2		13.3	ns
t <sub>PZH</sub> (1)	DIR	В		21.9		14.4		12.3		10.9	ns
t <sub>PZL</sub> <sup>(1)</sup>	DIK	J G		21		15.6		13.5		12.7	115

<sup>(1)</sup> The enable time is a calculated value, derived using the formula shown in the *Enable Times* section.



# 5.8 Switching Characteristics ( $V_{CCA} = 3.3V \pm 0.3V$ )

over recommended operating free-air temperature range,  $V_{CCA} = 3.3V \pm 0.3V$  (see Figure 6-1)

PARAMETER	PARAMETER FROM (INPUT)		TO V <sub>CCB</sub> = 1.8V ±0.15V			V <sub>CCB</sub> = 2.5V ±0.2V		3.3V V	V <sub>CCB</sub> = 5V ±0.5V		UNIT
	(INPOT)	(001701)	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	
t <sub>PLH</sub>	А	В	2.1	15.5	1.4	8	0.7	5.8	0.7	4.4	ns
t <sub>PHL</sub>	Α		2	12.6	1.3	7	0.8	5	0.7	4	115
t <sub>PLH</sub>	В	А	1.7	8.3	1.3	6.4	0.7	5.8	0.6	5.4	ns
t <sub>PHL</sub>	В		1.8	7.1	1.3	5.4	0.8	5	0.7	0.7 4.5	115
t <sub>PHZ</sub>	DIR	A	2.9	7.3	3	7.3	2.8	7.3	3.4	7.3	7.3 5.7 ns
t <sub>PLZ</sub>	DIK		1.8	5.6	1.6	5.6	2.2	5.7	2.2	5.7	
t <sub>PHZ</sub>	DIR	В	5.4	20.5	3.9	10.1	2.9	8.8	2.4	6.8	ns
t <sub>PLZ</sub>	DIK	В	3.3	14.5	2.9	7.8	2.4	7.1	1.7	4.9	115
t <sub>PZH</sub> (1)	DIR	A		22.8		14.2		12.9		10.3	ns
t <sub>PZL</sub> (1)	DIIX			27.6		15.5		13.8		11.3	115
t <sub>PZH</sub> (1)	DIR	В		21.1		13.6		11.5		10.1	ne
t <sub>PZL</sub> <sup>(1)</sup>	DIK	٥		19.9		14.3		12.3		11.3	ns

<sup>(1)</sup> The enable time is a calculated value, derived using the formula shown in the *Enable Times* section.

# 5.9 Switching Characteristics ( $V_{CCA} = 5V \pm 0.5V$ )

over recommended operating free-air temperature range,  $V_{CCA} = 5V \pm 0.5V$  (see Figure 6-1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V <sub>CCB</sub> = ±0.15	1.8V	V <sub>CCB</sub> = ±0.2		V <sub>CCB</sub> = ±0.3		V <sub>CCB</sub> = ±0.5		UNIT
	(INPOT)	(001701)	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	
t <sub>PLH</sub>	Α	В	1.9	15.1	1	7.5	0.6	5.4	0.5	3.9	ns
t <sub>PHL</sub>		В	1.8	12.2	0.9	6.2	0.7	4.5	0.5	3.5	115
t <sub>PLH</sub>	В	А	1.4	7.2	1	5.1	0.7	4.4	0.5	3.9	no
t <sub>PHL</sub>		_ ^	1.7	7	0.9	4.6	0.7	4	0.5	3.5	ns
t <sub>PHZ</sub>	DIR	A	2.1	5.4	2.2	5.4	2.2	5.5	2.2	5.4	ns
t <sub>PLZ</sub>	DIK	_ ^	0.9	3.8	1	3.8	0.7	3.7	0.7	3.7	115
t <sub>PHZ</sub>	DIR	В	4.8	20.2	2.5	9.8	1	8.5	2.5	6.5	ns
t <sub>PLZ</sub>	אוט	В	3.2	14.8	2.5	7.4	2.5	7	1.6	4.5	115
t <sub>PZH</sub> (1)	DIR	А		22		12.5		11.4		8.4	no
t <sub>PZL</sub> (1)	DIK	_ ^		27.2		14.4		12.5		10	ns
t <sub>PZH</sub> (1)	DIR	В		18.9		11.3		9.1		7.6	ne
t <sub>PZL</sub> <sup>(1)</sup>	DIK	ט		17.6		11.6		10		8.6	ns

<sup>(1)</sup> The enable time is a calculated value, derived using the formula shown in the *Enable Times* section.

Product Folder Links: SN74LVC1T45



# **5.10 Operating Characteristics**

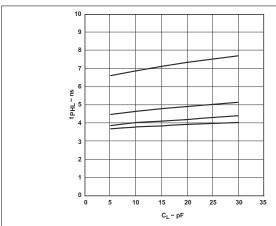
 $T_A = 25^{\circ}C$ 

	PARAMETER	TEST CONDITIONS	V <sub>CCA</sub> = V <sub>CCB</sub> = 1.8V	V <sub>CCA</sub> = V <sub>CCB</sub> = 2.5V	V <sub>CCA</sub> = V <sub>CCB</sub> = 3.3V	V <sub>CCA</sub> = V <sub>CCB</sub> = 5V	UNIT	
- (4)	A-port input, B-port output	$C_L = 0 pF$ ,	3	4	4	4	_	
C <sub>pdA</sub> (1)	B-port input, A-port output	f = 10 MHz, t <sub>r</sub> = t <sub>f</sub> = 1 ns	18	19	20	21	pF	
- (4)	A-port input, B-port output	$C_L = 0 pF,$	18	19	20	21	_	
C <sub>pdB</sub> (1)	B-port input, A-port output	f = 10 MHz, t <sub>r</sub> = t <sub>f</sub> = 1 ns	3	4	4	4	pF	

<sup>(1)</sup> Power dissipation capacitance per transceiver

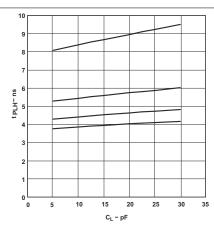


# **5.11 Typical Characteristics**



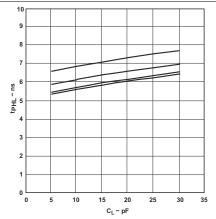
 $T_A = 25^{\circ}C, V_{CCA} = 1.8V$ 

Figure 5-1. Typical Propagation Delay (A to B) vs Load Capacitance



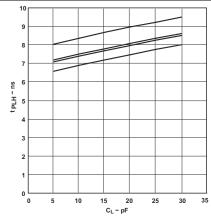
 $T_A = 25^{\circ}C, V_{CCA} = 1.8V$ 

Figure 5-2. Typical Propagation Delay (B to A) vs Load Capacitance



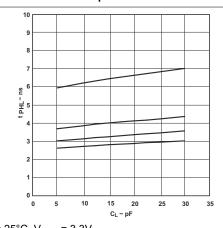
 $T_A = 25$ °C,  $V_{CCA} = 2.5V$ 

Figure 5-3. Typical Propagation Delay (A to B) vs Load Capacitance



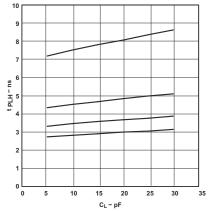
 $T_A = 25^{\circ}C, V_{CCA} = 2.5V$ 

Figure 5-4. Typical Propagation Delay (B to A) vs Load Capacitance



 $T_A = 25^{\circ}C, V_{CCA} = 3.3V$ 

Figure 5-5. Typical Propagation Delay (A to B) vs Load Capacitance



 $T_A = 25^{\circ}C, V_{CCA} = 3.3V$ 

Figure 5-6. Typical Propagation Delay (B to A) vs Load Capacitance

# **5.11 Typical Characteristics (continued)**

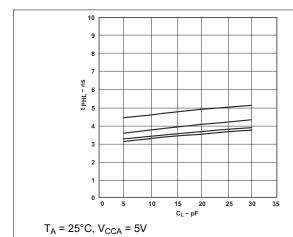
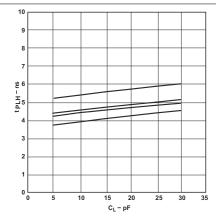


Figure 5-7. Typical Propagation Delay (A to B) vs Load Capacitance



 $T_A = 25$ °C,  $V_{CCA} = 5V$ 

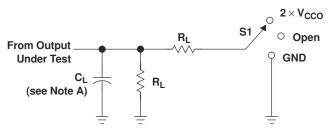
Figure 5-8. Typical Propagation Delay (B to A) vs Load Capacitance



 $V_{\text{CCA}}$ 

V<sub>CCA</sub>/2

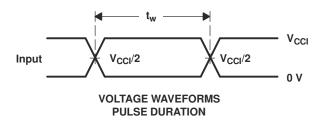
### **6 Parameter Measurement Information**



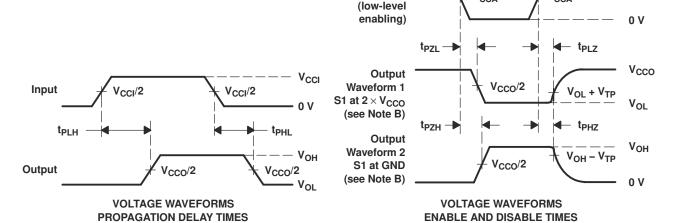
TEST	S1
t <sub>pd</sub>	Open
t <sub>PLZ</sub> /t <sub>PZL</sub>	$2\times\mathbf{V_{CCO}}$
t <sub>PHZ</sub> /t <sub>PZH</sub>	GND

**LOAD CIRCUIT** 

V <sub>CCO</sub>	CL	RL	V <sub>TP</sub>
1.8 V ± 0.15 V	15 pF	<b>2 k</b> Ω	0.15 V
2.5 V $\pm$ 0.2 V	15 pF	<b>2 k</b> Ω	0.15 V
3.3 V $\pm$ 0.3 V	15 pF	<b>2 k</b> Ω	0.3 V
5 V ± 0.5 V	15 pF	<b>2 k</b> Ω	0.3 V



V<sub>CCA</sub>/2



Output Control

NOTES: A.  $C_L$  includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low, except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high, except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR  $\leq$  10 MHz,  $Z_O$  = 50  $\Omega$ ,  $dv/dt \geq$  1 V/ns.
- D. The outputs are measured one at a time, with one transition per measurement.
- E.  $t_{PLZ}$  and  $t_{PHZ}$  are the same as  $t_{dis}$ .
- F.  $t_{PZL}$  and  $t_{PZH}$  are the same as  $t_{en}$ .
- G.  $t_{PLH}$  and  $t_{PHL}$  are the same as  $t_{pd}$ .
- H. V<sub>CCI</sub> is the V<sub>CC</sub> associated with the input port.
- I.  $V_{CCO}$  is the  $V_{CC}$  associated with the output port.
- J. All parameters and waveforms are not applicable to all devices.

Figure 6-1. Load Circuit and Voltage Waveforms

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### 7 Detailed Description

### 7.1 Overview

The SN74LVC1T45 is a single-bit, dual-supply, noninverting voltage level transceiver. Pin A and the direction control pin (DIR) are supported by  $V_{CCA}$  and pin B is supported by  $V_{CCB}$ . The A port is able to accept I/O voltages ranging from 1.65V to 5.5V, while the B port can accept I/O voltages from 1.65V to 5.5V. The high on the DIR allows data transmissions from A to B and a low on the DIR allows data transmissions from B to A.

### 7.2 Functional Block Diagram

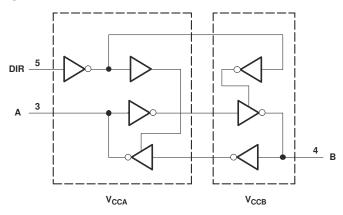


Figure 7-1. Logic Diagram (Positive Logic)

### 7.3 Feature Description

# 7.3.1 Fully Configurable Dual-Rail Design Allows Each Port to Operate Over the Full 1.65V to 5.5V Power-Supply Range

Both  $V_{CCA}$  and  $V_{CCB}$  can be supplied at any voltage between 1.65V and 5.5V, making the device suitable for translating between any of the voltage nodes (1.8V, 2.5V, 3.3V, and 5V).

### 7.3.2 Support High Speed Translation

The SN74LVC1T45 device supports high data rate applications. The translated signal data rate can be up to 420Mbps when the signal is translated from 3.3V to 5V.

#### 7.3.3 I<sub>off</sub> Supports Partial Power-Down Mode Operation

The inputs and outputs for this device enter a high-impedance state when the device is powered down, inhibiting current backflow into the device. The maximum leakage into or out of any input or output pin on the device is specified by I<sub>off</sub> in the *Electrical Charateristics*.

### 7.3.4 Balanced High-Drive CMOS Push-Pull Outputs

A balanced output allows the device to sink and source similar currents. The high drive capability of this device creates fast edges into light loads so impedance matching and load conditions should be considered to prevent ringing. Additionally, the outputs of this device are capable of driving larger currents than the device can sustain without being damaged. Two outputs can be connected together for a stronger output drive strength. The electrical and thermal limits defined in the *Absolute Maximum Ratings* must be followed at all times.

### 7.3.5 Glitch-Free Power Supply Sequencing

Either supply rail may be powered on or off in any order without producing a glitch on the I/Os (that is, where the output erroneously transitions to VCC when it should be held low or vice versa). Glitches of this nature can be misinterpreted by a peripheral as a valid data bit, which could trigger a false device reset of the peripheral, a false device configuration of the peripheral, or even a false data initialization by the peripheral.



### 7.3.6 V<sub>cc</sub> Isolation

The I/Os of both ports will enter a high-impedance state when either of the supplies are at GND, while the other supply is still connected to the device. The maximum leakage into or out of any input or output pin on the device is specified by I<sub>off</sub> in the *Electrical Characteristics*.

### 7.4 Device Functional Modes

Table 7-1. Function Table<sup>(1)</sup>

INPUT DIR	OPERATION
L	B data to A bus
Н	A data to B bus

Input circuits of the data I/Os always are active.

Product Folder Links: SN74LVC1T45

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# 8 Applications and Implementation

#### Note

Information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI's customers are responsible for determining suitability of components for their purposes, as well as validating and testing their design implementation to confirm system functionality.

### 8.1 Application Information

The SN74LVC1T45 device can be used in level-translation applications for interfacing devices or systems operating at different interface voltages with one another. The maximum data rate can be up to 420Mbps when device translates signals from 3.3V to 5V.

### 8.2 Typical Application

### 8.2.1 Unidirectional Logic Level-Shifting Application

Figure 8-1 shows an example of the SN74LVC1T45 being used in a unidirectional logic level-shifting application.

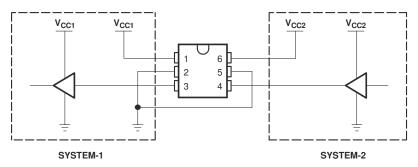


Figure 8-1. Unidirectional Logic Level-Shifting Application

### 8.2.1.1 Design Requirements

For this design example, use the parameters listed in Table 8-1.

**Table 8-1. Design Parameters** 

DESIGN PARAMETER	EXAMPLE VALUE
Input voltage range	1.65V to 5.5V
Output voltage range	1.65V to 5.5V

### 8.2.1.2 Detailed Design Procedure

To begin the design process, determine the following:

- · Input voltage range
- Use the supply voltage of the device that is driving the SN74LVC1T45 device to determine the input voltage range. For a valid logic high the value must exceed the  $V_{IH}$  of the input port. For a valid logic low the value must be less than the  $V_{IL}$  of the input port.
- Output voltage range
- Use the supply voltage of the device that the SN74LVC1T45 device is driving to determine the output voltage range.

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#### 8.2.1.3 Application Curve

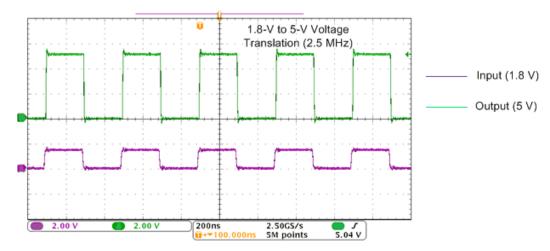


Figure 8-2. Translation Up (1.8V to 5V) at 2.5 MHz

### 8.2.2 Bidirectional Logic Level-Shifting Application

Figure 8-3 shows the SN74LVC1T45 being used in a bidirectional logic level-shifting application. Because the SN74LVC1T45 does not have an output-enable (OE) pin, the system designer should take precautions to avoid bus contention between SYSTEM-1 and SYSTEM-2 when changing directions.

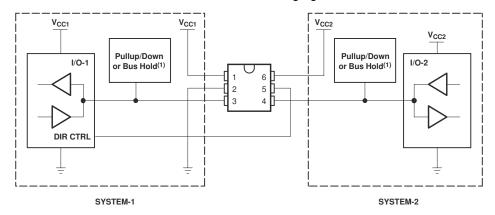


Figure 8-3. Bidirectional Logic Level-Shifting Application

### 8.2.2.1 Design Requirements

See Section 8.2.1.1.

#### 8.2.2.2 Detailed Design Procedure

Table 8-2 shows data transmission from SYSTEM-1 to SYSTEM-2 and then from SYSTEM-2 to SYSTEM-1.

Table 8-2. SYSTEM-1 and SYSTEM-2 Data Transmission

STATE	DIR CTRL	I/O-1	I/O-2	DESCRIPTION
1	Н	Out	In	SYSTEM-1 data to SYSTEM-2
2	Н	Hi-Z	Hi-Z	SYSTEM-2 is getting ready to send data to SYSTEM-1. I/O-1 and I/O-2 are disabled. The bus-line state depends on pullup or pulldown. <sup>(1)</sup>
3	L	Hi-Z	Hi-Z	DIR bit is flipped. I/O-1 and I/O-2 still are disabled. The bus-line state depends on pullup or pulldown. <sup>(1)</sup>
4	L	In	Out	SYSTEM-2 data to SYSTEM-1

SYSTEM-1 and SYSTEM-2 must use the same conditions, that is, both pullup or both pulldown.

Product Folder Links: SN74LVC1T45

#### 8.2.2.2.1 Enable Times

Calculate the enable times for the SN74LVC1T45 using the following formulas:

- $t_{PZH}$  (DIR to A) =  $t_{PLZ}$  (DIR to B) +  $t_{PLH}$  (B to A)
- $t_{PZI}$  (DIR to A) =  $t_{PHZ}$  (DIR to B) +  $t_{PHI}$  (B to A)
- $t_{PZH}$  (DIR to B) =  $t_{PLZ}$  (DIR to A) +  $t_{PLH}$  (A to B)
- $t_{PZL}$  (DIR to B) =  $t_{PHZ}$  (DIR to A) +  $t_{PHL}$  (A to B)

In a bidirectional application, these enable times provide the maximum delay from the time the DIR bit is switched until an output is expected. For example, if the SN74LVC1T45 initially is transmitting from A to B, then the DIR bit is switched; the B port of the device must be disabled before presenting it with an input. After the B port has been disabled, an input signal applied to it appears on the corresponding A port after the specified propagation delay.

#### 8.2.2.3 Application Curve

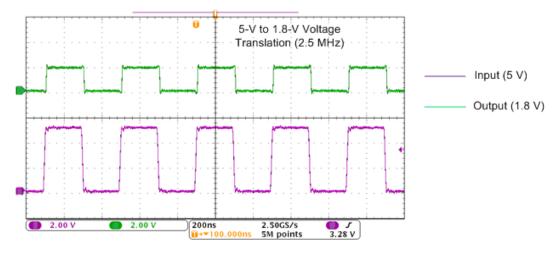


Figure 8-4. Translation Down (5V to 1.8V) at 2.5 MHz

### 8.3 Power Supply Recommendations

Always apply a ground reference to the GND pins first. This device is designed for glitch free power sequencing without any supply sequencing requirements such as ramp order or ramp rate.

This device was designed with various power supply sequencing methods in mind to help prevent unintended triggering of downstream devices, as described in *Glitch-free Power Supply Sequencing*.

#### 8.4 Layout

#### 8.4.1 Layout Guidelines

To ensure reliability of the device, the following common printed-circuit board layout guidelines are recommended:

- Bypass capacitors should be used on power supplies.
- Short trace lengths should be used to avoid excessive loading.
- Placing pads on the signal paths for loading capacitors or pullup resistors to help adjust rise and fall times of signals depends on the system requirements

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### 8.4.2 Layout Example



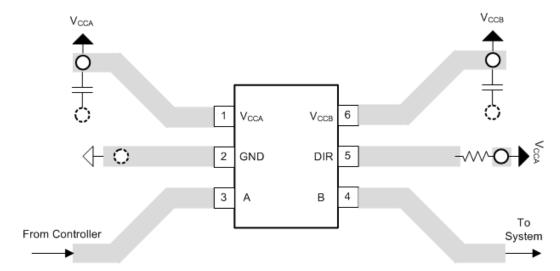


Figure 8-5. Layout Example

### 9 Device and Documentation Support

### 9.1 Documentation Support

#### 9.1.1 Related Documentation

For related documentation see the following:

Texas Instruments, Implications of Slow or Floating CMOS Inputs

### 9.2 Receiving Notification of Documentation Updates

To receive notification of documentation updates, navigate to the device product folder on ti.com. Click on *Notifications* to register and receive a weekly digest of any product information that has changed. For change details, review the revision history included in any revised document.

### 9.3 Support Resources

TI E2E<sup>™</sup> support forums are an engineer's go-to source for fast, verified answers and design help — straight from the experts. Search existing answers or ask your own question to get the quick design help you need.

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#### 9.4 Trademarks

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### 9.5 Electrostatic Discharge Caution



This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

### 9.6 Glossary

TI Glossary

This glossary lists and explains terms, acronyms, and definitions.

### 10 Revision History

NOTE: Page numbers for previous revisions may differ from page numbers in the current version.

С	hanges from Revision M (November 2022) to Revision N (June 2024)	Page
•	Updated the Power Supply Recommendations section	17
•	hanna from Bavisian I. (Eshman, 2017) to Bavisian M (Navambar 2022)	Dawa
C	hanges from Revision L (February 2017) to Revision M (November 2022)	Page
•	Updated the numbering format for tables, figures, and cross-references throughout the document	1
•	Updated the thermals in the <i>Thermal Information</i> section	5
•	Updated the Switching Characterisitcs sections: extended some minimum specifications for lower dela	ys <mark>7</mark>
•	Updated the Ioff Supports Partial Power-Down Mode Operation section	•
•	Added the Balanced High-Drive CMOS Push-Pull Outputs and $V_{CC}$ Isolation sections	

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# 11 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.

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### **PACKAGING INFORMATION**

Orderable Device	Status (1)	Package Type	Package Drawing	Pins	Package Qty	Eco Plan	Lead finish/ Ball material (6)	MSL Peak Temp	Op Temp (°C)	Device Marking (4/5)	Samples
SN74LVC1T45DBVR	ACTIVE	SOT-23	DBV	6	3000	RoHS & Green	NIPDAU   SN	Level-1-260C-UNLIM	-40 to 85	(2PUH, CT15, CT1F, CT1R)	Samples
SN74LVC1T45DBVRE4	ACTIVE	SOT-23	DBV	6	3000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 85	(CT15, CT1F, CT1R)	Samples
SN74LVC1T45DBVRG4	ACTIVE	SOT-23	DBV	6	3000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 85	(CT15, CT1F, CT1R)	Samples
SN74LVC1T45DBVT	ACTIVE	SOT-23	DBV	6	250	RoHS & Green	NIPDAU   SN	Level-1-260C-UNLIM	-40 to 85	(CT15, CT1F, CT1R)	Samples
SN74LVC1T45DBVTG4	ACTIVE	SOT-23	DBV	6	250	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 85	(CT15, CT1F, CT1R)	Samples
SN74LVC1T45DCKR	ACTIVE	SC70	DCK	6	3000	RoHS & Green	NIPDAU   SN	Level-1-260C-UNLIM	-40 to 85	(TA5, TAF, TAR)	Samples
SN74LVC1T45DCKRE4	ACTIVE	SC70	DCK	6	3000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 85	(TA5, TAF, TAR)	Samples
SN74LVC1T45DCKRG4	ACTIVE	SC70	DCK	6	3000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 85	(TA5, TAF, TAR)	Samples
SN74LVC1T45DCKT	ACTIVE	SC70	DCK	6	250	RoHS & Green	NIPDAU   SN	Level-1-260C-UNLIM	-40 to 85	(TA5, TAF, TAR)	Samples
SN74LVC1T45DCKTE4	ACTIVE	SC70	DCK	6	250	RoHS & Green	SN	Level-1-260C-UNLIM	-40 to 85	(TA5, TAF, TAR)	Samples
SN74LVC1T45DPKR	ACTIVE	USON	DPK	6	5000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 85	TA7	Samples
SN74LVC1T45DRLR	ACTIVE	SOT-5X3	DRL	6	4000	RoHS & Green	NIPDAU   NIPDAUAG	Level-1-260C-UNLIM	-40 to 85	(1JX, TA7, TAR)	Samples
SN74LVC1T45DRLRG4	ACTIVE	SOT-5X3	DRL	6	4000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 85	(1JX, TA7, TAR)	Samples
SN74LVC1T45YZPR	ACTIVE	DSBGA	YZP	6	3000	RoHS & Green	SNAGCU	Level-1-260C-UNLIM	-40 to 85	(TA2, TA7, TAN)	Samples

<sup>(1)</sup> The marketing status values are defined as follows: **ACTIVE:** Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

**NRND:** Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design. **PREVIEW:** Device has been announced but is not in production. Samples may or may not be available.

**OBSOLETE**: TI has discontinued the production of the device.

### PACKAGE OPTION ADDENDUM

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(2) RoHS: TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

Green: TI defines "Green" to mean the content of Chlorine (CI) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

- (3) MSL, Peak Temp. The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.
- (4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.
- (5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.
- (6) Lead finish/Ball material Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

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#### OTHER QUALIFIED VERSIONS OF SN74LVC1T45:

Automotive: SN74LVC1T45-Q1

Enhanced Product: SN74LVC1T45-EP

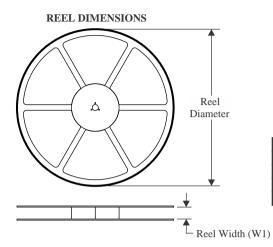
#### NOTE: Qualified Version Definitions:

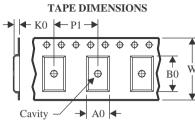
- Automotive Q100 devices qualified for high-reliability automotive applications targeting zero defects
- Enhanced Product Supports Defense, Aerospace and Medical Applications



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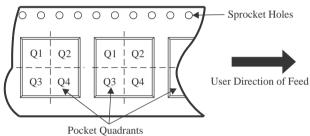
### TAPE AND REEL INFORMATION





A0	Dimension designed to accommodate the component width
В0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

### QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



#### \*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
SN74LVC1T45DBVR	SOT-23	DBV	6	3000	180.0	8.4	3.2	3.2	1.4	4.0	8.0	Q3
SN74LVC1T45DBVR	SOT-23	DBV	6	3000	180.0	8.4	3.2	3.2	1.4	4.0	8.0	Q3
SN74LVC1T45DBVRE4	SOT-23	DBV	6	3000	180.0	8.4	3.2	3.2	1.4	4.0	8.0	Q3
SN74LVC1T45DBVRE4	SOT-23	DBV	6	3000	180.0	8.4	3.2	3.2	1.4	4.0	8.0	Q3
SN74LVC1T45DBVRG4	SOT-23	DBV	6	3000	180.0	8.4	3.2	3.2	1.4	4.0	8.0	Q3
SN74LVC1T45DBVRG4	SOT-23	DBV	6	3000	180.0	8.4	3.2	3.2	1.4	4.0	8.0	Q3
SN74LVC1T45DBVT	SOT-23	DBV	6	250	180.0	8.4	3.2	3.2	1.4	4.0	8.0	Q3
SN74LVC1T45DBVT	SOT-23	DBV	6	250	180.0	8.4	3.2	3.2	1.4	4.0	8.0	Q3
SN74LVC1T45DBVTG4	SOT-23	DBV	6	250	180.0	8.4	3.2	3.2	1.4	4.0	8.0	Q3
SN74LVC1T45DBVTG4	SOT-23	DBV	6	250	180.0	8.4	3.2	3.2	1.4	4.0	8.0	Q3
SN74LVC1T45DCKR	SC70	DCK	6	3000	178.0	9.0	2.4	2.5	1.2	4.0	8.0	Q3
SN74LVC1T45DCKRE4	SC70	DCK	6	3000	178.0	9.0	2.4	2.5	1.2	4.0	8.0	Q3
SN74LVC1T45DCKT	SC70	DCK	6	250	178.0	9.0	2.4	2.5	1.2	4.0	8.0	Q3
SN74LVC1T45DPKR	USON	DPK	6	5000	180.0	9.5	1.75	1.75	0.7	4.0	8.0	Q2
SN74LVC1T45DRLR	SOT-5X3	DRL	6	4000	180.0	8.4	2.0	1.8	0.75	4.0	8.0	Q3
SN74LVC1T45YZPR	DSBGA	YZP	6	3000	178.0	9.2	1.02	1.52	0.63	4.0	8.0	Q1



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\*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
SN74LVC1T45DBVR	SOT-23	DBV	6	3000	210.0	185.0	35.0
SN74LVC1T45DBVR	SOT-23	DBV	6	3000	210.0	185.0	35.0
SN74LVC1T45DBVRE4	SOT-23	DBV	6	3000	210.0	185.0	35.0
SN74LVC1T45DBVRE4	SOT-23	DBV	6	3000	210.0	185.0	35.0
SN74LVC1T45DBVRG4	SOT-23	DBV	6	3000	210.0	185.0	35.0
SN74LVC1T45DBVRG4	SOT-23	DBV	6	3000	210.0	185.0	35.0
SN74LVC1T45DBVT	SOT-23	DBV	6	250	210.0	185.0	35.0
SN74LVC1T45DBVT	SOT-23	DBV	6	250	210.0	185.0	35.0
SN74LVC1T45DBVTG4	SOT-23	DBV	6	250	210.0	185.0	35.0
SN74LVC1T45DBVTG4	SOT-23	DBV	6	250	210.0	185.0	35.0
SN74LVC1T45DCKR	SC70	DCK	6	3000	180.0	180.0	18.0
SN74LVC1T45DCKRE4	SC70	DCK	6	3000	180.0	180.0	18.0
SN74LVC1T45DCKT	SC70	DCK	6	250	180.0	180.0	18.0
SN74LVC1T45DPKR	USON	DPK	6	5000	184.0	184.0	19.0
SN74LVC1T45DRLR	SOT-5X3	DRL	6	4000	210.0	185.0	35.0
SN74LVC1T45YZPR	DSBGA	YZP	6	3000	220.0	220.0	35.0





### NOTES:

- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

  2. This drawing is subject to change without notice.

  3. Body dimensions do not include mold flash or protrusion. Mold flash and protrusion shall not exceed 0.15 per side.

  4. Falls within JEDEC MO-203 variation AB.





NOTES: (continued)

5. Publication IPC-7351 may have alternate designs.

6. Solder mask tolerances between and around signal pads can vary based on board fabrication site.





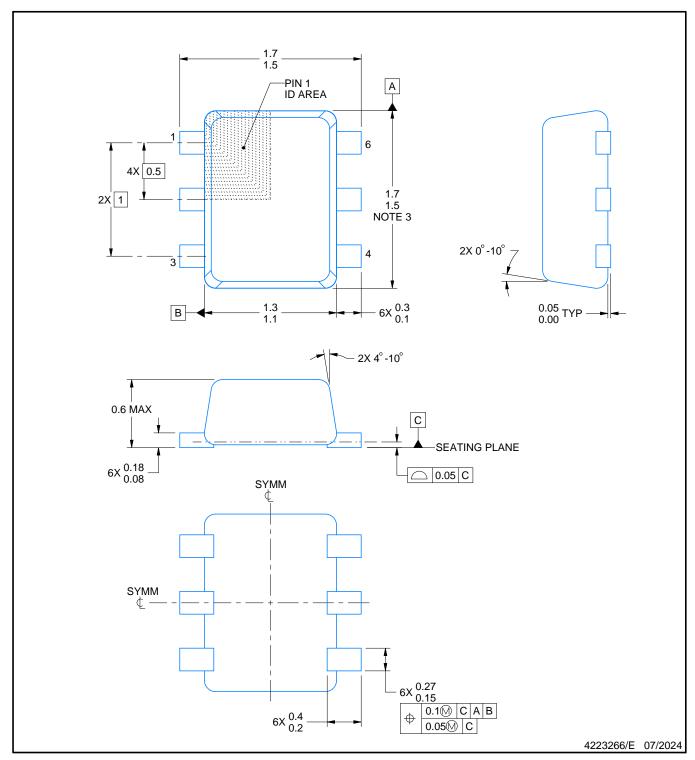
NOTES: (continued)

- 7. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 8. Board assembly site may have different recommendations for stencil design.





PLASTIC SMALL OUTLINE



#### NOTES:

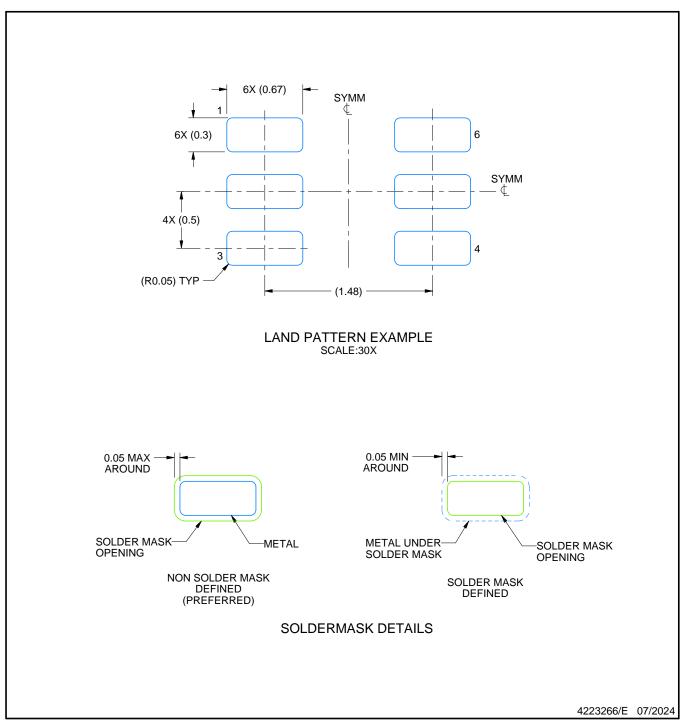
- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

  2. This drawing is subject to change without notice.

  3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not
- exceed 0.15 mm per side.
  4. Reference JEDEC registration MO-293 Variation UAAD



PLASTIC SMALL OUTLINE

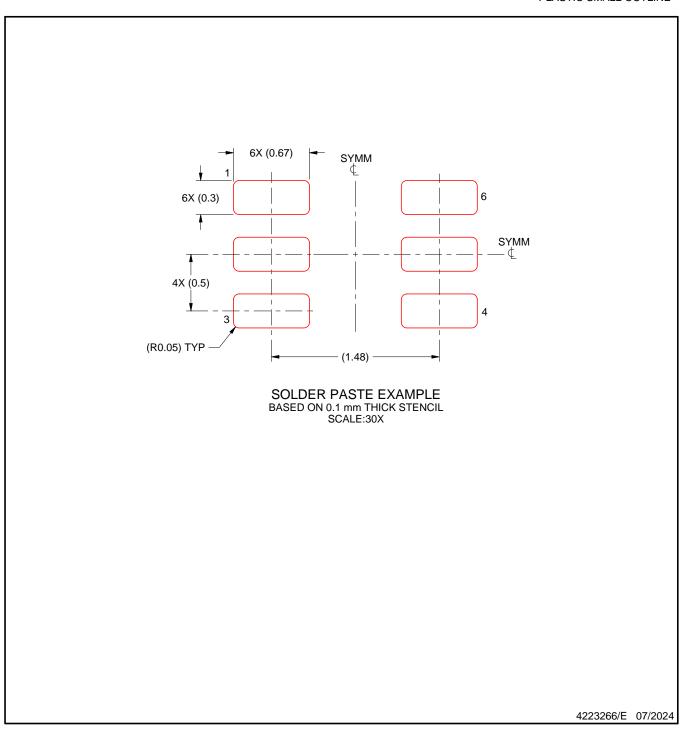


NOTES: (continued)

- 5. Publication IPC-7351 may have alternate designs.
- 6. Solder mask tolerances between and around signal pads can vary based on board fabrication site.7. Land pattern design aligns to IPC-610, Bottom Termination Component (BTC) solder joint inspection criteria.



PLASTIC SMALL OUTLINE



NOTES: (continued)

- 8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 9. Board assembly site may have different recommendations for stencil design.







### NOTES:

- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

  2. This drawing is subject to change without notice.

  3. Body dimensions do not include mold flash or protrusion. Mold flash and protrusion shall not exceed 0.25 per side.

- 4. Leads 1,2,3 may be wider than leads 4,5,6 for package orientation.
- 5. Refernce JEDEC MO-178.





NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.





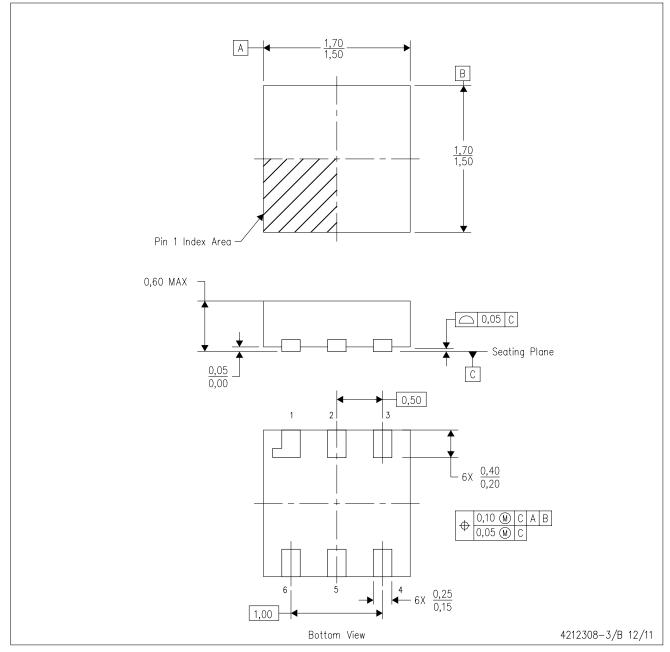
NOTES: (continued)

- 8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 9. Board assembly site may have different recommendations for stencil design.



# DPK (S-PUSON-N6)

# PLASTIC SMALL OUTLINE NO-LEAD

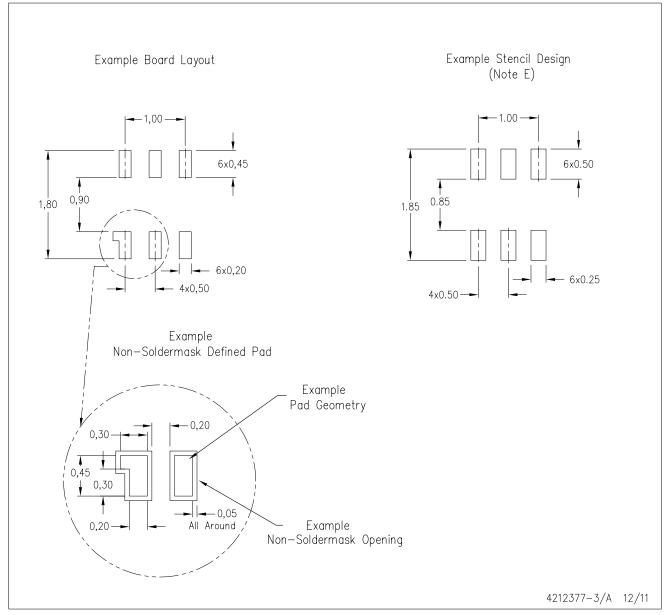


 A. All linear dimensions are in millimeters. Dimensioning and tolerancing per ASME Y14.5M-1994.
 B. This drawing is subject to change without notice. NOTES:



# DPK (S-PUSON-N6)

# PLASTIC SMALL OUTLINE NO-LEAD



- NOTES: A. All linear dimensions are in millimeters.
  - B. This drawing is subject to change without notice.
  - C. Publication IPC-7351 is recommended for alternate designs.
  - D. Customers should contact their board fabrication site for minimum solder mask web tolerances between signal pads.
  - E. Maximum stencil thickness 0,127 mm (5 mils). All linear dimensions are in millimeters.
  - F. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Refer to IPC 7525 for stencil design considerations.
  - G. Side aperture dimensions over-print land for acceptable area ratio > 0.66. Customer may reduce side aperture dimensions if stencil manufacturing process allows for sufficient release at smaller opening.





DIE SIZE BALL GRID ARRAY



#### NOTES:

NanoFree Is a trademark of Texas Instruments.

- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

  2. This drawing is subject to change without notice.
- 3. NanoFree<sup>™</sup> package configuration.



DIE SIZE BALL GRID ARRAY



NOTES: (continued)

4. Final dimensions may vary due to manufacturing tolerance considerations and also routing constraints. For more information, see Texas Instruments literature number SBVA017 (www.ti.com/lit/sbva017).



DIE SIZE BALL GRID ARRAY



NOTES: (continued)

5. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release.



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